

RELIABILITY MONITOR

DS1210S JAN '98 MONITOR-HYUNDAI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9750	DN738347AAA	16 PIN SOIC	HYUNDAI-KOREA (HEI)
PROCESS Single Poly, Single Metal 3.0 μm POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21776	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22233	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.08E+07		0
P21287	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22234	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22235	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22236	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1210S APR '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9811	DN752523AAC	16 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 3.0 μm POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22232	INFANT LIFE	125°C, 7.0 VOLTS	233	48	HOUR	0
P22262	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21895	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22263	TEMP CYCLE	-55 TO 125°C	38	400	CYCL	0
			38	1000	CYCL	0
TOTAL:						0
P22264	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22265	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1210S JUL '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210S	C1	9813	DN801581AAC	16 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 3.0 μm POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22330	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22398	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22213	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22399	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22400	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22401	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1232S APR '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232	C1	9805	DN737280ABA	16 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 3.0 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22047	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22145	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21901	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22146	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22147	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22148	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1232S JUL '98 MONITOR - HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232S	C1	9821	DL809263AAC	16 PIN SOIC	HYUNDAI-KOREA (HEI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22324	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22370	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22222	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22371	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22372	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22373	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1233Z-10 APR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9752	DM740622ACA	SOT-223	CARSEM
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22075	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
P22185	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.07E+07		0
P21903	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
TOTAL:						0
P22186	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22187	HAST	120°C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
P22188	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1233 JUL '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9828	DM819256ABA	SOT-223	CARSEM
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22421	INFANT LIFE	125°C, 7.0 VOLTS	229	48	HOUR	0
TOTALS:			239	FAIL RATE (Fits): DEVICE HRS: 3.84E+06		0
P22348	HIGH TEMP STORAGE	125°C	233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	233	3	PASS	0
TOTAL:						0
P22523	HAST	120°C, 85%R.H.,5.5V	71	100	HOUR	0
TOTAL:						0
P22524	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1267E AUG '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267	A1	9824	DK745514ABB	20 PIN TSSOP	ANAM-PI (AAPI)
PROCESS Single Poly, Single Metal 1.2 μm Implanted poly1					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22597	INFANT LIFE	125°C, 6.0V,-4.0V	229	48	HOUR	0
TOTALS:			651	FAIL RATE (Fits): DEVICE HRS: 1.41E+06		0
P22495	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22663	AUTOCLAVE	121°C STEAM, UNBIASED	34	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1302Z DEC '97 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9745	DN736077AAC	8 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21627	INFANT LIFE	125°C, 6.0 VOLTS	232	48	HOUR	0
P21731	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P21228	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21732	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21733	BIASED MOISTURE	85/85, 5.5 VOLTS	74	274	HOUR	0
			74	959	HOUR	0
TOTAL:						0
P21734	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1302 JUN '98 MONITOR-ANAM KOREA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	A3	9808	DN750310ABC	8 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22282	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
P22349	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	FAIL RATE (Fits): DEVICE HRS: 1.13E+07		0
P22211	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22350	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22351	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			76	959	HOUR	0
TOTAL:						0
P22352	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1302Z MAR '98 MONITOR-HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9808	DL750312ABA	8 PIN SOIC	HYUNDAI-KOREA (HEI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21826	INFANT LIFE	125°C, 6.0 VOLTS	229	48	HOUR	0
P21972	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	75	336	HOUR	0
		125°C, 6.0 VOLTS	75	1000	HOUR	0
TOTALS:			83	DEVICE HRS: 1.11E+07		0
P21736	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21973	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21974	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			75	959	HOUR	0
TOTAL:						0
P21975	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1315 SEP '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1315	B1	9825	DK806519AAA	16 PIN PDIP	ANAM-PI (AAPI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22496	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			233	FAIL RATE (Fits): DEVICE HRS: 3.92E+06		0
P22538	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22539	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1620S DEC '97 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9740	DJ724413AAD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21529	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P21852	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.09E+07		0
P21254	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21853	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21854	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
P22149	HIGH TEMP STORAGE	150°C	49	336	HOUR	0
			49	1000	HOUR	0
		ELEC TEST	49	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1620 JUN '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9741	DJ723284AAF	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β:	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22198	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P22287	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.09E+07		0
P22129	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22288	TEMP CYCLE	-55 TO 125°C	39	300	CYCL	0
			33	1000	CYCL	0
TOTAL:						0
P22289	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
P22409	HIGH TEMP STORAGE	150°C	46	336	HOUR	0
			46	1000	HOUR	0
	ELEC TEST		45	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1620 MAR '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9746	DJ723286AAC	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22173	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
P22271	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	72	336	HOUR	0
		125°C, 7.0 VOLTS	72	1000	HOUR	0
TOTALS:			32	FAIL RATE (Fits): DEVICE HRS: 2.90E+07		0
P22067	HIGH TEMP STORAGE	125°C	236	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	236	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	236	3	PASS	0
TOTAL:						0
P22272	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22273	HAST	120°C, 85%R.H.,5.5V	70	100	HOUR	0
TOTAL:						0
P22408	HIGH TEMP STORAGE	150°C	47	336	HOUR	0
			45	1000	HOUR	0
	ELEC TEST		45	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1620S SEPT. '98 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9746	DJ711527ABD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22599	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
TOTALS:			239	FAIL RATE (Fits): DEVICE HRS: 3.84E+06		0
P22501	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0

RELIABILITY MONITOR

DS1621S DEC '97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9740	DM727709AAA	8 PIN SOIC	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21367	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
P21727	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21256	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21728	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			39	1000	CYCL	0
TOTAL:						0
P21729	BIASED MOISTURE	85/85, 5.5 VOLTS	65	274	HOUR	0
			65	959	HOUR	0
TOTAL:						0
P22121	HIGH TEMP STORAGE	150°C	50	336	HOUR	0
			50	1000	HOUR	0
		ELEC TEST	50	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1621 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9745	DM734572AAD	8 PIN SOIC	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22200	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P22283	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	71	336	HOUR	0
		125°C, 7.0 VOLTS	71	1000	HOUR	0
TOTALS:			32	DEVICE HRS: 2.87E+07		0
P22131	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22284	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			36	1000	CYCL	0
TOTAL:						0
P22337	HIGH TEMP STORAGE	150°C	43	336	HOUR	0
			43	1000	HOUR	0
	ELEC TEST		43	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS1621S MAR '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9749	DM705419ABA	8 PIN SOIC	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22276	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
P22342	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	68	336	HOUR	0
		125°C, 7.0 VOLTS	67	1000	HOUR	0
TOTALS:			34	FAIL RATE (Fits): DEVICE HRS: 2.72E+07		0
P22202	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22343	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			39	1000	CYCL	0
TOTAL:						0

RELIABILITY MONITOR

DS1621S SEPT.'98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A7	9807	DN744346ABA	8 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22590	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
TOTALS:			231	FAIL RATE (Fits): DEVICE HRS: 3.96E+06		0
P22503	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	240	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	240	3	PASS	0
TOTAL:						0

RELIABILITY MONITOR

DS1669S-10 NOV.'97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21187	INFANT LIFE	125°C, 7.0 VOLTS	232	48	HOUR	0
		ELEC TEST	38	48	HOUR	0
P21819	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	76	1000	HOUR	0
TOTALS:			30	DEVICE HRS: 3.04E+07		0
P20997	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21820	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			35	1000	CYCL	0
TOTAL:						0
P21821	BIASED MOISTURE	85/85, 5.5 VOLTS	73	274	HOUR	0
			69	959	HOUR	0
TOTAL:						0
P21822	HIGH TEMP STORAGE	150°C	38	336	HOUR	0
			36	1000	HOUR	0
		ELEC TEST	36	1000	HOUR	0

RELIABILITY MONITOR

DS1669S-10 NOV.'97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

RELIABILITY MONITOR

DS17485 FEB.'98 MONITOR,D.P.-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9730	DN713701AAE	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22032	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
P22303	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	76	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.04E+07		0
P21607	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P22304	TEMP CYCLE	-55 TO 125°C	50	300	CYCL	0
			50	1000	CYCL	0
TOTAL:						0
P22305	HAST	120°C, 85%R.H.,5.5V	63	100	HOUR	0
TOTAL:						0
P22306	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS17485 MAY '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9814	DN803023AAD	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22308	INFANT LIFE	125°C, 7.0 VOLTS	230	48	HOUR	0
P22467	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P22010	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:						0
P22468	TEMP CYCLE	-55 TO 125°C	48	300	CYCL	0
			48	1000	CYCL	0
TOTAL:						0
P22469	HAST	120°C, 85%R.H.,5.5V	65	100	HOUR	0
TOTAL:						0
P22470	AUTOCLAVE	121°C STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS17485 AUG '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9819	DN807687AAA	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22472	INFANT LIFE	125°C, 7.0 VOLTS	233	48	HOUR	0
TOTALS:			235	FAIL RATE (Fits):		0
			DEVICE HRS: 3.89E+06			
P22378	HIGH TEMP STORAGE	125°C	237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	237	3	PASS	0
TOTAL:			0			
P22528	HAST	120°C, 85%R.H.,5.5V	65	100	HOUR	0
TOTAL:			0			
P22529	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:			0			

RELIABILITY MONITOR

DS2108 FEB.'98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9740	DN729120AAC	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21556	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21690	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			66	FAIL RATE (Fits): DEVICE HRS: 1.38E+07		0
P21471	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21691	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21692	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21693	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2108 MAY '98 MONITOR, D.P-ANAM, K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9741	DN729121ABA	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22138	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0
P22153	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0
		125°C, 6.0 VOLTS	77	1000	HOUR	0
TOTALS:			81	DEVICE HRS: 1.13E+07		0
FAIL RATE (Fits):						
P22012	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	238	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:			0			
P22154	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:			0			
P22155	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:			0			
P22156	AUTOCLAVE	121°C STEAM, UNBIASED	39	98	HOUR	0
TOTAL:			0			

RELIABILITY MONITOR

DS2108 AUG '98 MONITOR, D.P-ANAM, K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9747	DN722653BAB	24 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS	
P22456	INFANT LIFE	125°C, 6.0 VOLTS	234	48	HOUR	0	
P22484	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS	77	336	HOUR	0	
		125°C, 6.0 VOLTS	77	1000	HOUR	0	
TOTALS:			81	DEVICE HRS: 1.13E+07		0	
FAIL RATE (Fits):							
P22382	HIGH TEMP STORAGE	125°C	238	24	HOUR		
	MOISTURE SOAK	30°C/60% R.H.	238	144	HOUR		
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0	
TOTAL:							0
P22487	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0	
TOTAL:							0

RELIABILITY MONITOR

DS2153 JUN '98 MONITOR-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9740	DN725561AAB	44 PIN PLCC	ANAM-KOREA (AICL)
PROCESS Double Poly, Single Metal 0.8 μm Capacitor					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22294	INFANT LIFE	125°C, 6.0 VOLTS	237	48	HOUR	0
P22334	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	76	336	HOUR	0
		125°C, 7.0 VOLTS	76	1000	HOUR	0
TOTALS:			33	DEVICE HRS: 2.80E+07		0
P22133	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22335	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P22336	AUTOCLAVE	121°C STEAM, UNBIASED	100	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2153Q MAR '98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9734	DN720030AAB	44 PIN PLCC	ANAM-KOREA (AICL)
PROCESS Double Poly, Single Metal 0.8 μm Capacitor					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22292	INFANT LIFE	125°C, 6.0 VOLTS	237	48	HOUR	0
P22331	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			32	DEVICE HRS: 2.84E+07		0
P21818	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22332	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P22333	AUTOCLAVE	121°C STEAM, UNBIASED	100	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2153Q SEPT.'98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9749	DN733468AAB	44 PIN PLCC	ANAM-KOREA (AICL)
PROCESS Double Poly, Single Metal 0.8 μm Capacitor					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22556	INFANT LIFE	125°C, 6.0 VOLTS	236	48	HOUR	0
TOTALS:			FAIL RATE (Fits): 635	DEVICE HRS: 1.44E+06		0
P22498	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22639	AUTOCLAVE	121°C STEAM, UNBIASED	98	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2175S JUL '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2175S	D1	9811	DN803119AAE	16 PIN SOIC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 2.0 μm Pfield					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22328	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22402	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22227	TEMP CYCLE	-55 TO 125°C	238	10	CYCL	
	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22403	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22404	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22405	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2180A MAY '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2180A	B3	9810	DN752567AAB	44 PIN PLCC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 2.0 μm Pfield					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22196	INFANT LIFE	125°C, 7.0 VOLTS	236	48	HOUR	0
P22277	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.02E+07		0
P22014	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P22278	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P22279	HAST	120°C, 85%R.H.,5.5V	59	100	HOUR	0
TOTAL:						0
P22280	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2181A FEB.'98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181A	A2	9741	DN728030AAB	44 PIN PLCC	ANAM-KOREA (AICL)
PROCESS Single Poly, Single Metal 2.0 μm Pfield					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21699	INFANT LIFE	125°C, 7.0 VOLTS	237	48	HOUR	0
P21777	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.09E+07		0
P21493	TEMP CYCLE	-55 TO 125°C	241	10	CYCL	
	HIGH TEMP STORAGE	125°C	241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	241	3	PASS	0
TOTAL:						0
P21778	TEMP CYCLE	-55 TO 125°C	60	300	CYCL	0
			60	1000	CYCL	0
TOTAL:						0
P21779	HAST	120°C, 85%R.H.,5.5V	60	100	HOUR	0
TOTAL:						0
P21780	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS21S07A FEB '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9802	DM741735ABC	20 PIN TSSOP	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21637	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21694	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21469	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P21695	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21696	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21697	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS21S07A MAY '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9815	DM805323AAE	20 PIN TSSOP	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22171	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22242	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22102	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22243	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22244	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22245	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS21S07AE AUG '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9820	DM807703AAE	20 PIN TSSOP	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Negative zero tempco poly					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22466	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			233	3.92E+06	DEVICE HRS:	0
P22380	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
TOTAL:						0
P22491	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS232 JUN '98 MONITOR - OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723ABD	16 PIN PDIP	OMEDATA
PROCESS Single Poly, Single Metal 5.0 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22122	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			233	FAIL RATE (Fits): DEVICE HRS: 3.92E+06		0
P22167	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:			0			
P22168	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:			0			
P22169	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:			0			

RELIABILITY MONITOR

DS232 JUN '98 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723ABD	16 PIN PDIP	OMEDATA
PROCESS Single Poly, Single Metal 5.0 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22166	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
		TOTALS:			FAIL RATE (Fits):	34
P22167	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				
P22168	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				
P22169	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

RELIABILITY MONITOR

DS232 MAR '98 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723AAB	16 PIN PDIP	OMEDATA
PROCESS Single Poly, Single Metal 5.0 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21726	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21751	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P21752	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21753	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21754	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS232 SEPTEMBER '98 MONITOR - OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747726AAA	16 PIN PDIP	OMEDATA
PROCESS Single Poly, Single Metal 5.0 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22499	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			FAIL RATE (Fits): 233	DEVICE HRS: 3.92E+06		0
P22548	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2401 MAR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22162	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
		TOTALS:			FAIL RATE (Fits):	34
P22163	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				
P22164	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				
P22165	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				

RELIABILITY MONITOR

DS2401 MAR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22152	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			234	FAIL RATE (Fits): DEVICE HRS: 3.91E+06		0
P22163	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22164	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22165	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2401 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9805	DM743297ADA	T0-92	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22123	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22157	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22158	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22159	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22160	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2401 SEPT. '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9814	DM747716ACA	T0-92	CARSEM
PROCESS Single Poly, Single Metal 0.8 μ m Standard Process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22504	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
TOTALS:			234	FAIL RATE (Fits): DEVICE HRS: 3.91E+06		0
P22534	HAST	120°C, 85%R.H.,5.5V	77	100	HOUR	0
TOTAL:						0
P22535	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2502 JUN '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B4	9814	DM751356AFA	8 PIN SOIC	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm EPROM process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22251	INFANT LIFE	125°C, 7.0 VOLTS	193	48	HOUR	0
TOTALS:			283	3.24E+06	DEVICE HRS:	0
P22135	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST	238	0		0
TOTAL:						0
P22298	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22299	BIASED MOISTURE	85/85, 5.5 VOLTS	88	274	HOUR	0
			88	959	HOUR	0
TOTAL:						0
P22300	HIGH TEMP STORAGE	150°C	40	336	HOUR	0
			40	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS2502 SEPT.'98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B6	9827	DM811458AAB	8 PIN SOIC	CARSEM
PROCESS Single Poly, Single Metal 0.8 μm EPROM process					

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22573	INFANT LIFE	125°C, 7.0 VOLTS	233	48	HOUR	0
TOTALS:			234	FAIL RATE (Fits): DEVICE HRS: 3.91E+06		0
P22506	HIGH TEMP STORAGE	125°C	238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.	238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST	237	0		0
TOTAL:			237	0		0

RELIABILITY MONITOR

DS5002 APR 98 'MONITOR,DP.- CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9806	DM743264AAC	80 PIN PQFP	CARSEM
PROCESS Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22249	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	0
P22319	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.02E+07		0
P21907	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P22320	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22322	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS5002 JUL '98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9822	DM808095AAE	80 PIN PQFP	CARSEM
PROCESS Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22364	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	0
TOTALS:			276	DEVICE HRS: 3.32E+06		0
P22247	HIGH TEMP STORAGE	125°C	203	25	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P22444	AUTOCLAVE	121°C STEAM, UNBIASED	39	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS5002F JAN.'98 MONITOR,D.P.-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002F	A3	9738	DM720028AAC	80 PIN PQFP	CARSEM
PROCESS Single Poly, Single Metal 1.2 μm Buried contacts w/silicided poly					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21352	INFANT LIFE	125°C, 7.0 VOLTS	199	48	HOUR	0
TOTALS:			275	DEVICE HRS: 3.34E+06		0
P21282	HIGH TEMP STORAGE	125°C	203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.	203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE	203	3	PASS	0
TOTAL:						0
P21472	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21473	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
			41	959	HOUR	0
TOTAL:						0
P21474	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS80320 APR '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9810	DK748103AAB	40 PIN PDIP	ANAM-PI (AAPI)
PROCESS Single Poly, Single Metal 0.8 μm Poly silicide					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P21893	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P21964	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
P21965	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P21966	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P21967	AUTOCLAVE	121°C STEAM, UNBIASED	35	96	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS80320 JUL '98 MONITOR - ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9815	DK804253AAA	40 PIN PDIP	ANAM-PI (AAPI)
PROCESS Single Poly, Single Metal 0.8 μm Poly silicide					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
P22230	INFANT LIFE	125°C, 7.0 VOLTS	234	48	HOUR	0
P22309	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS	77	336	HOUR	0
		125°C, 7.0 VOLTS	77	1000	HOUR	0
TOTALS:			30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
P22310	TEMP CYCLE	-55 TO 125°C	40	300	CYCL	0
			40	1000	CYCL	0
TOTAL:						0
P22311	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
P22312	AUTOCLAVE	121°C STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0